

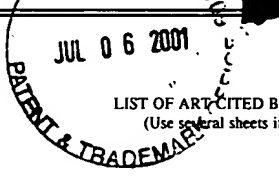
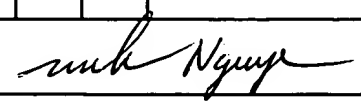
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-16804	PRIORITY SERIAL NO. 09/137,629		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David R. Hembree			
				PRIORITY FILING DATE August 21, 1998	PRIORITY GROUP 2858		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,560,216	12/24/85	Egawa			
	AB	4,754,555	7/5/88	Stillman			
	AC	5,475,317	12/12/95	Smith			
	AD	5,495,667	3/5/96	Farnworth et al.			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE	S/N: 09/032,184; Filed 2/27/98; Akram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendment filed 3/3/00; Amendment filed 8/23/09; Original Application filed 2/27/98; Pending Claims.					
VN	AF	Advertisement for Probe Technology; www.idinet.com ; Interconnect Devices, Inc.; 1 page; 3/6/98					
VN	AG	Good Things Come In Small BGA/CSP Packages; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98					
VN	AH	Product Description for Double Ended Probes, B1052 Series; www.testprobe.com/products/b1052.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AI	Product Description for Test Centers, RM-500 Series Probes, www.testprobe.com/products/rm500.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products; www.testprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AK	Product Description for Ball Grid Probe B1303-C3; www.testprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AL	Product Description for Test Socket Contacts; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98					
EXAMINER <i>mu Nguye</i>				DATE CONSIDERED 03/22/2002			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1684		SERIAL NO. 09/827,248	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; color: white; font-weight: bold; font-size: 1.2em;"> O I P E JUL 29 2002 PATENT & TRADEMARK OFFICE </div> </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
				APPLICANT Micron Technology, Inc.			
				FILING DATE April 4, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA	6,004,471	12/21/1999	Chuang	—		
VN	AB	5,550,526	8/27/1996	Mottahead	—		
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
EXAMINER <i>rmh Nguyen</i>				DATE CONSIDERED 10/18/2002			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

EVO 77333999

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1684		SERIAL NO. 09 827,248	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE April 4, 2001		GROUP 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
✓	✓	1,000,000	3/29/1999	Nagasaki et al.			
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
EXAMINER <i>mh Nguyen</i>				DATE CONSIDERED 10/18/2000			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

S:\M122\1684\VD5..wpd A2711051243N

Form PTO-1449		 #4		ATTY. DOCKET NO. MI22-1684		SERIAL NO. 09/827,248	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE April 4, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA	5,378,311	1/3/95	Nagayama et al.			
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
EXAMINER			DATE CONSIDERED				
			03/22/2002				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							